

BUL1102E

HIGH VOLTAGE FAST-SWITCHING NPN POWER TRANSISTOR

- HIGH VOLTAGE CAPABILITY
- LOW SPREAD OF DYNAMIC PARAMETERS
- MINIMUM LOT-TO-LOT SPREAD FOR RELIABLE OPERATION
- VERY HIGH SWITCHING SPEED

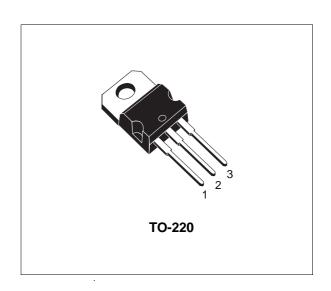
APPLICATIONS

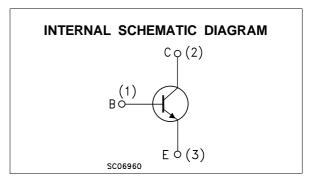
■ FOUR LAMP ELECTRONIC BALLAST FOR: 120 V MAINS IN PUSH-PULL CONFIGURATION; 277 V MAINS IN HALF BRIDGE CURRENT FEED CONFIGURATION.

DESCRIPTION

The device is manufactured using high voltage Multi Epitaxial Planar technology for high switching speeds and high voltage capability. It uses a Cellular Emitter structure with planar edge termination to enhance switching speeds while maintaining a wide RBSOA.

Thanks to an increased intermediate layer, it has an intrinsic ruggedness which enables the transistor to withstand a high collector current level during Breakdown condition, without using the transil protection usually necessary in typical converters for lamp ballast.





ABSOLUTE MAXIMUM RATINGS

| Symbol | Parameter | Value | Unit |
|------------------|---|------------|------|
| V _{CES} | Collector-Emitter Voltage (V _{BE} = 0) | 1100 | V |
| V _{CEO} | Collector-Emitter Voltage (I _B = 0) | 450 | V |
| V _{EBO} | Emitter-Base Voltage (I _C = 0) | 12 | V |
| Ic | Collector Current | 4 | А |
| I _{CM} | Collector Peak Current (t _p <5 ms) | 8 | Α |
| I _B | Base Current | 2 | А |
| I _{BM} | Base Peak Current (t _p <5 ms) | 4 | Α |
| P _{tot} | Total Dissipation at T _c = 25 °C | 70 | W |
| T _{stg} | Storage Temperature | -65 to 150 | °C |
| Tj | Max. Operating Junction Temperature | 150 | °C |

March 2003 1/6

THERMAL DATA

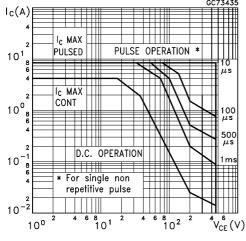
| R _{thj-case} Thermal Resistance Junction-Case | Max | 1.78 | °C/W | |
|--|-----|------|------|--|
|--|-----|------|------|--|

ELECTRICAL CHARACTERISTICS ($T_{case} = 25$ °C unless otherwise specified)

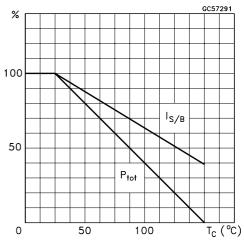
| Symbol | Parameter | Test Conditions | | Min. | Тур. | Max. | Unit |
|---------------------------|---|---|--|----------|------|------------|----------|
| I _{CES} | Collector Cut-off Current (V _{BE} = 0) | V _{CE} = 1100 V | | | | 100 | μА |
| I _{EBO} | Emitter Cut-off Current (I _B = 0) | V _{EB} = 12 V | | | | 1 | mA |
| $V_{\text{CEO(sus)}^{*}}$ | Collector-Emitter Sustaining Voltage (I _B = 0) | I _C = 100 mA | | 450 | | | V |
| V _{CE(sat)} * | Collector-Emitter Saturation Voltage | I _C = 2 A | I _B = 400 mA | | | 1.5 | V |
| V _{BE(sat)} * | Base-Emitter Saturation Voltage | I _C = 2 A | I _B = 400 mA | | | 1.5 | V |
| h _{FE} * | DC Current Gain | I _C = 250 mA I _C = 2 A | V _{CE} = 5 V V _{CE} = 5 V | 35 12 | | 70 20 | |
| t _s | RESISTIVE LOAD Storage Time Fall Time | I _C = 2.5 A I _{B1} = 0.5 A T _P = 30 μs | | | | 2.5 300 | μs ns |
| Ear | Avalanche Energy | $L = 2 \text{ mH}$ $I_{BR} \le 2.5 \text{A}$ (see figure 1) | C = 1.8 nF 25°C < T _C <125°C | 6 | | | mJ |

^{*} Pulsed: Pulse duration = 300 μs, duty cycle 1.5 %

Safe Operating Areas

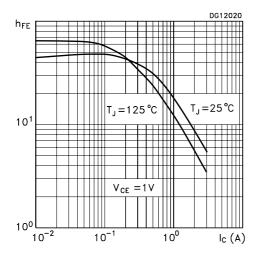


Derating Curve

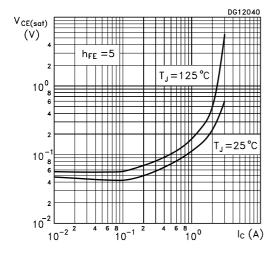


2/6

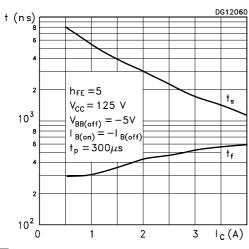
DC Current Gain



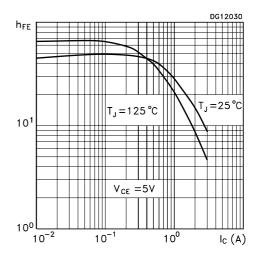
Collector Emitter Saturation Voltage



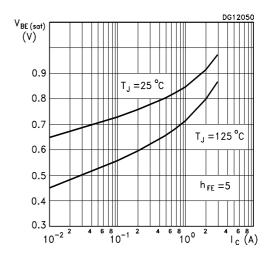
Switching Time Resistive Load



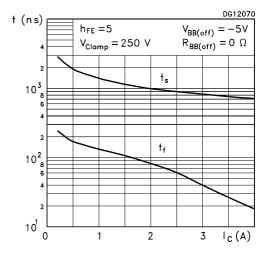
DC Current Gain



Base Emitter Saturation Voltage



Switching Time Inductive Load



477

Reverse Biased SOA

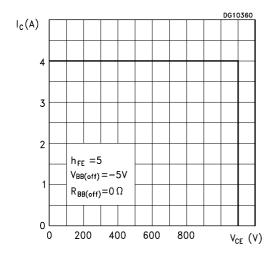


Figure 1: Energy Rating Test Circuit

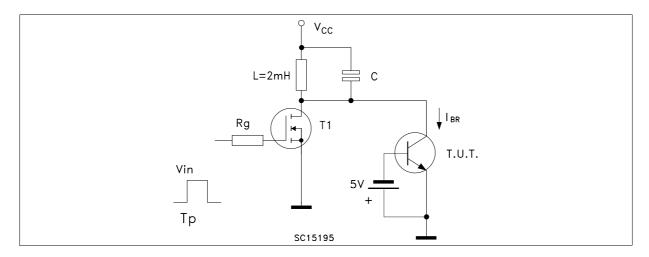
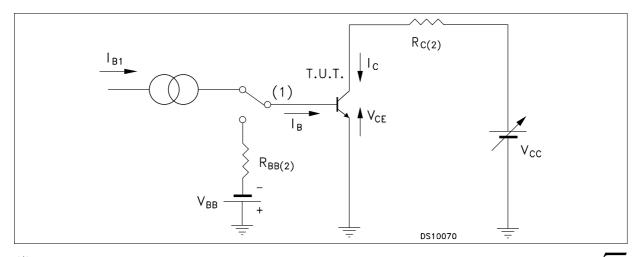


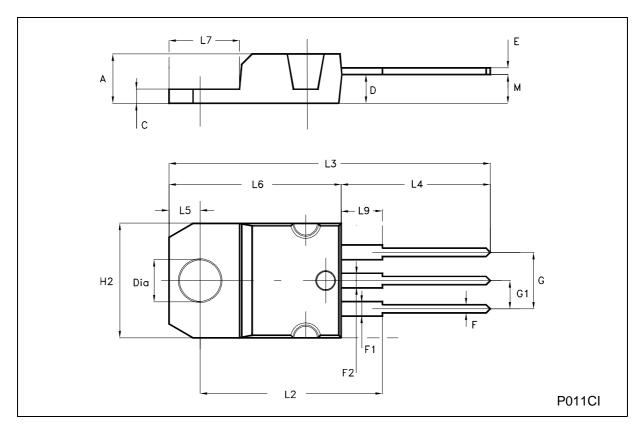
Figure 2: Resistive Load Switching Test Circuit



4/6

TO-220 MECHANICAL DATA

| DIM | mm | | | inch | | | |
|------|-------|-------|-------|-------|-------|-------|--|
| DIM. | MIN. | TYP. | MAX. | MIN. | TYP. | MAX. | |
| Α | 4.40 | | 4.60 | 0.173 | | 0.181 | |
| С | 1.23 | | 1.32 | 0.048 | | 0.052 | |
| D | 2.40 | | 2.72 | 0.094 | | 0.107 | |
| E | 0.49 | | 0.70 | 0.019 | | 0.027 | |
| F | 0.61 | | 0.88 | 0.024 | | 0.034 | |
| F1 | 1.14 | | 1.70 | 0.044 | | 0.067 | |
| F2 | 1.14 | | 1.70 | 0.044 | | 0.067 | |
| G | 4.95 | | 5.15 | 0.194 | | 0.202 | |
| G1 | 2.40 | | 2.70 | 0.094 | | 0.106 | |
| H2 | 10.00 | | 10.40 | 0.394 | | 0.409 | |
| L2 | | 16.40 | | | 0.645 | | |
| L4 | 13.00 | | 14.00 | 0.511 | | 0.551 | |
| L5 | 2.65 | | 2.95 | 0.104 | | 0.116 | |
| L6 | 15.25 | | 15.75 | 0.600 | | 0.620 | |
| L7 | 6.20 | | 6.60 | 0.244 | | 0.260 | |
| L9 | 3.50 | | 3.93 | 0.137 | | 0.154 | |
| М | | 2.60 | | | 0.102 | | |
| DIA. | 3.75 | | 3.85 | 0.147 | | 0.151 | |



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47/